United States Patent [19]
Tanabe

[11] **Des. 270,337**
[45] ** **Aug. 30, 1983**

[54] **MULTIMETER**

[75] Inventor: **Masahiro Tanabe**, Tokyo, Japan

[73] Assignee: **Akigawa Electronic Corporation,** Tokyo, Japan

[**] Term: 14 years

[21] Appl. No.: **164,145**

[22] Filed: **Jun. 30, 1980**

[30] **Foreign Application Priority Data**

Feb. 8, 1980 [JP] Japan 55-4228

[51] **Int. Cl.** .... **D10—04**
[52] **U.S. Cl.** **D10/78**
[58] **Field of Search** .... D10/75, 78, 46, 57; 324/73, 76 R, 115, 156

[56] **References Cited**

U.S. PATENT DOCUMENTS

D. 223,196 3/1972 Andreaggi D10/78
D. 246,767 12/1977 Needham D10/78
D. 253,227 10/1979 Buck D10/78

OTHER PUBLICATIONS

Amprobe Inst. Test. Equip. Cat. 9/78, p. 6–Multimeter at top right.
Scientific Educational Products–Multimeter on front.

Primary Examiner—Nelson C. Holtje
Attorney, Agent, or Firm—Fleit, Jacobson & Cohn

[57] **CLAIM**

The ornamental design for multimeter, substantially as described and shown.

DESCRIPTION

FIG. **1** is a front perspective view of a multimeter showing my new design;
FIG. **2** is a front elevational view thereof;
FIG. **3** is a left side elevational view thereof;
FIG. **4** is a right side elevational view thereof;
FIG. **5** is a rear elevational view thereof;
FIG. **6** is a top plan view thereof; and
FIG. **7** is a bottom plan view thereof.

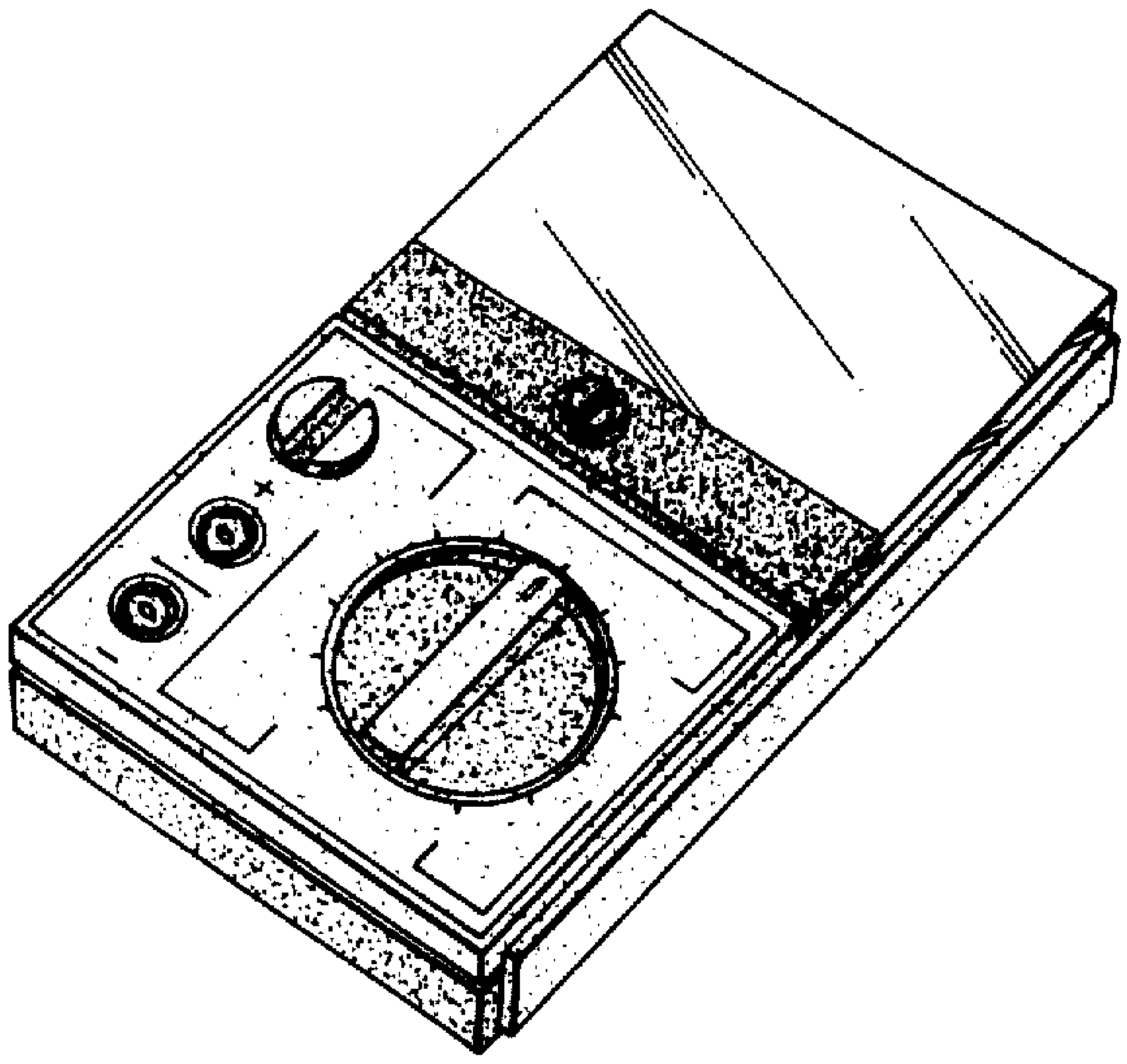

FIG. 1

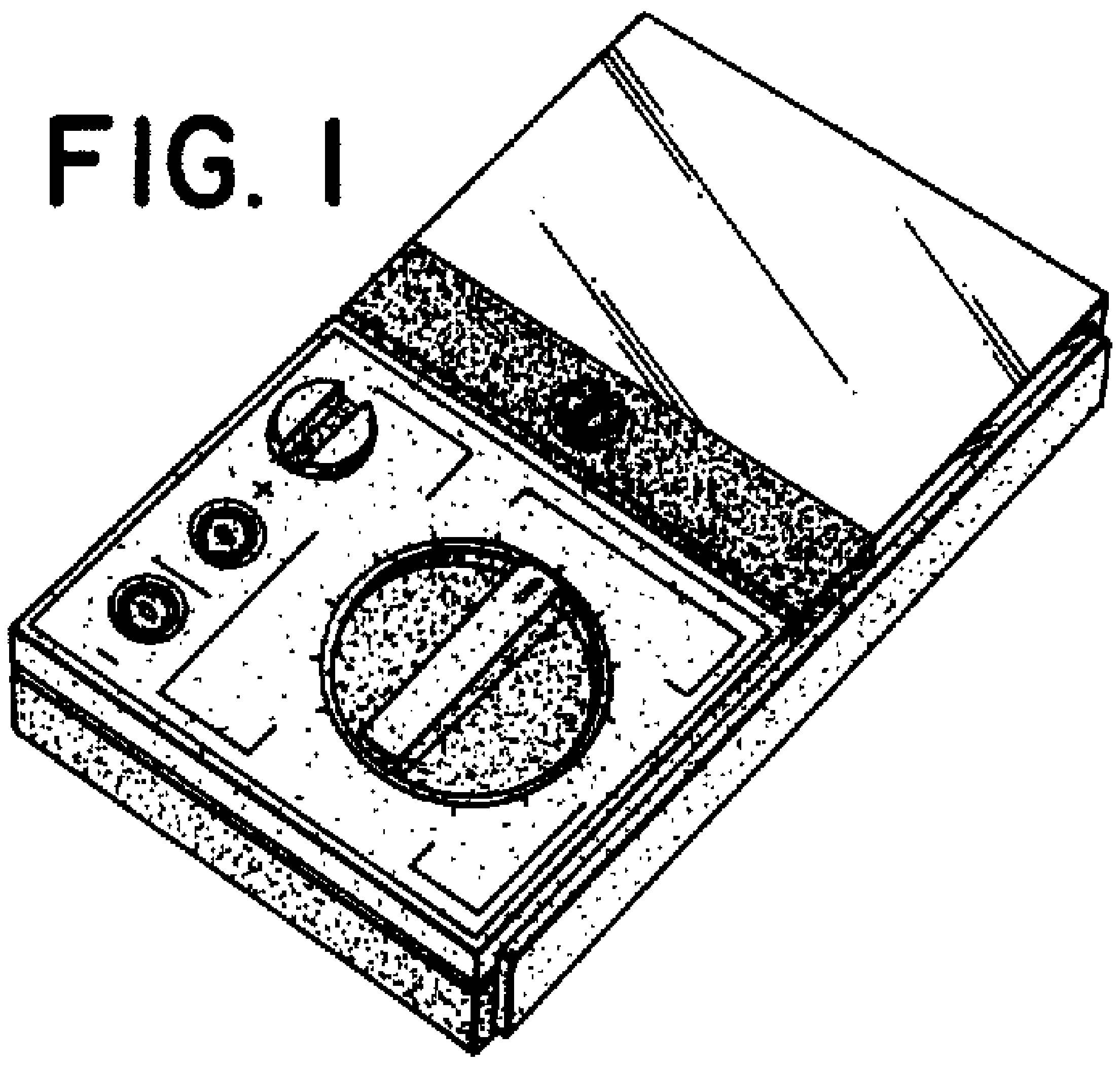

FIG. 2

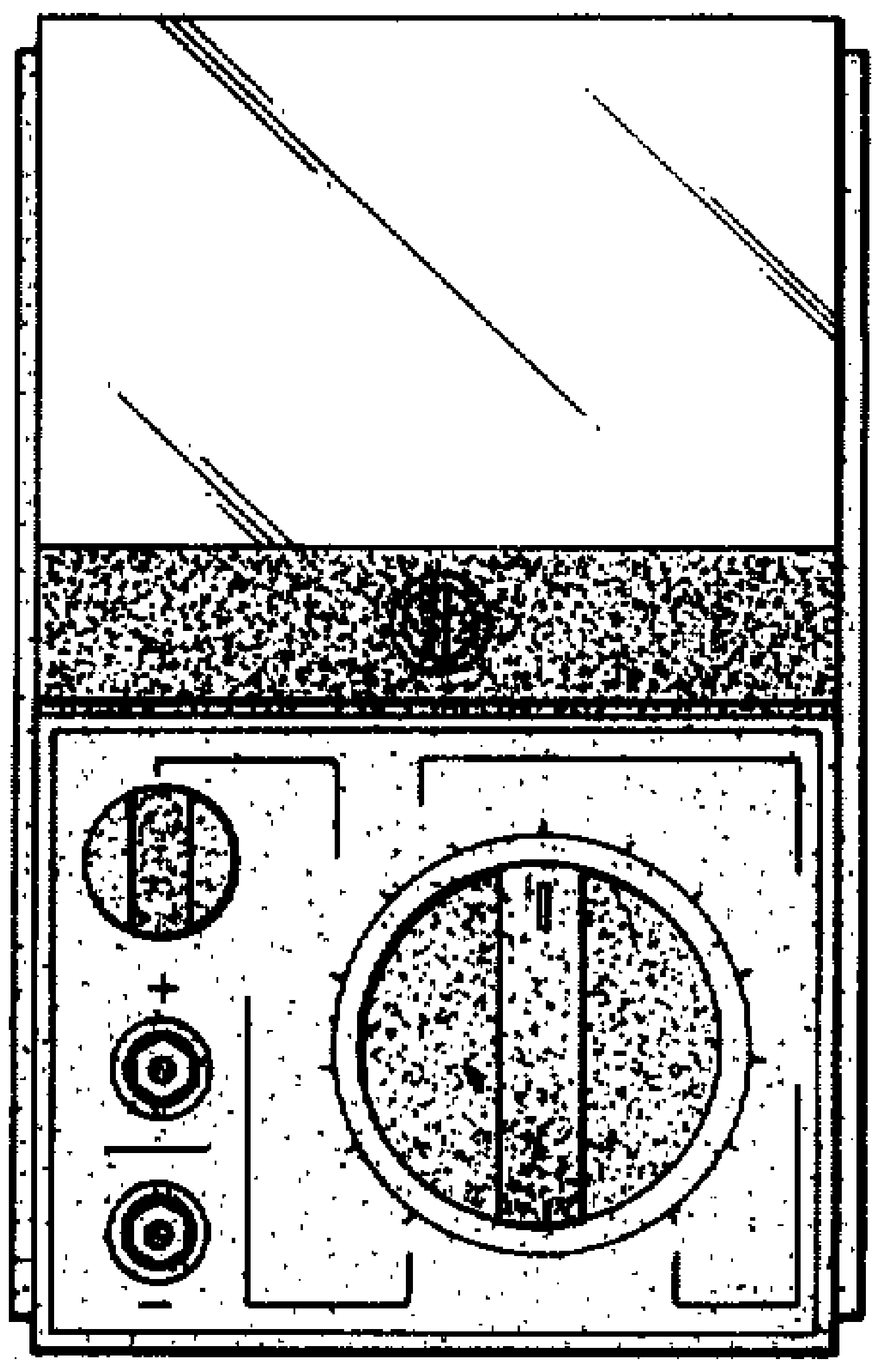

FIG. 3

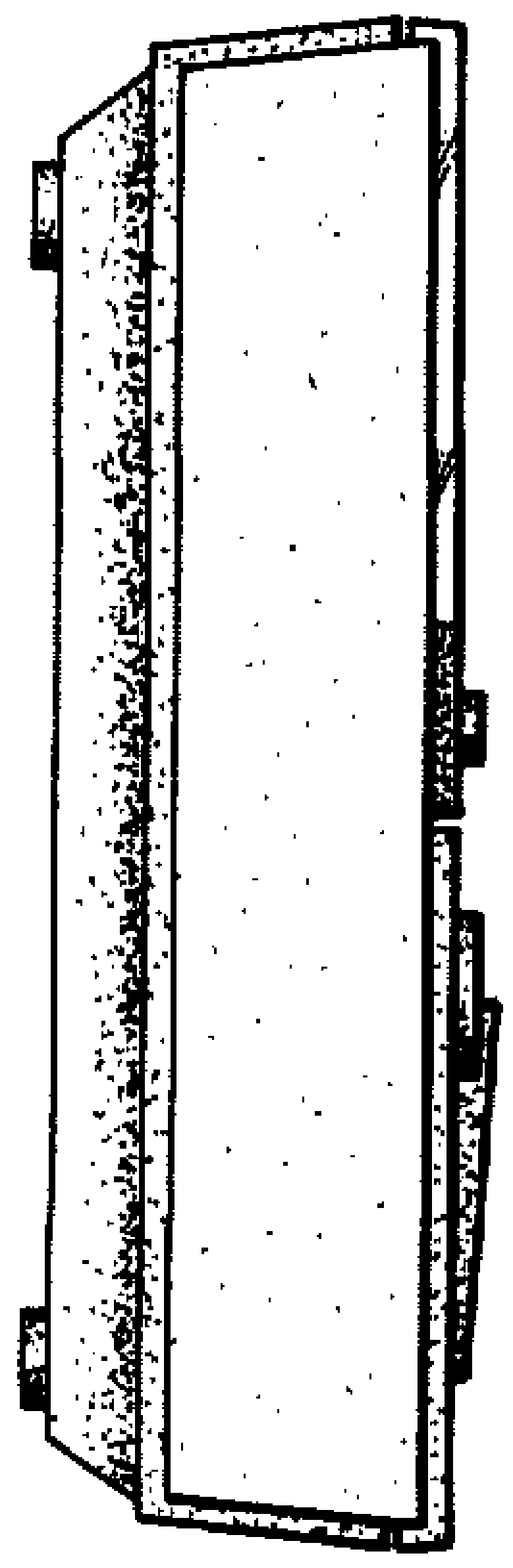

FIG. 4

FIG. 5

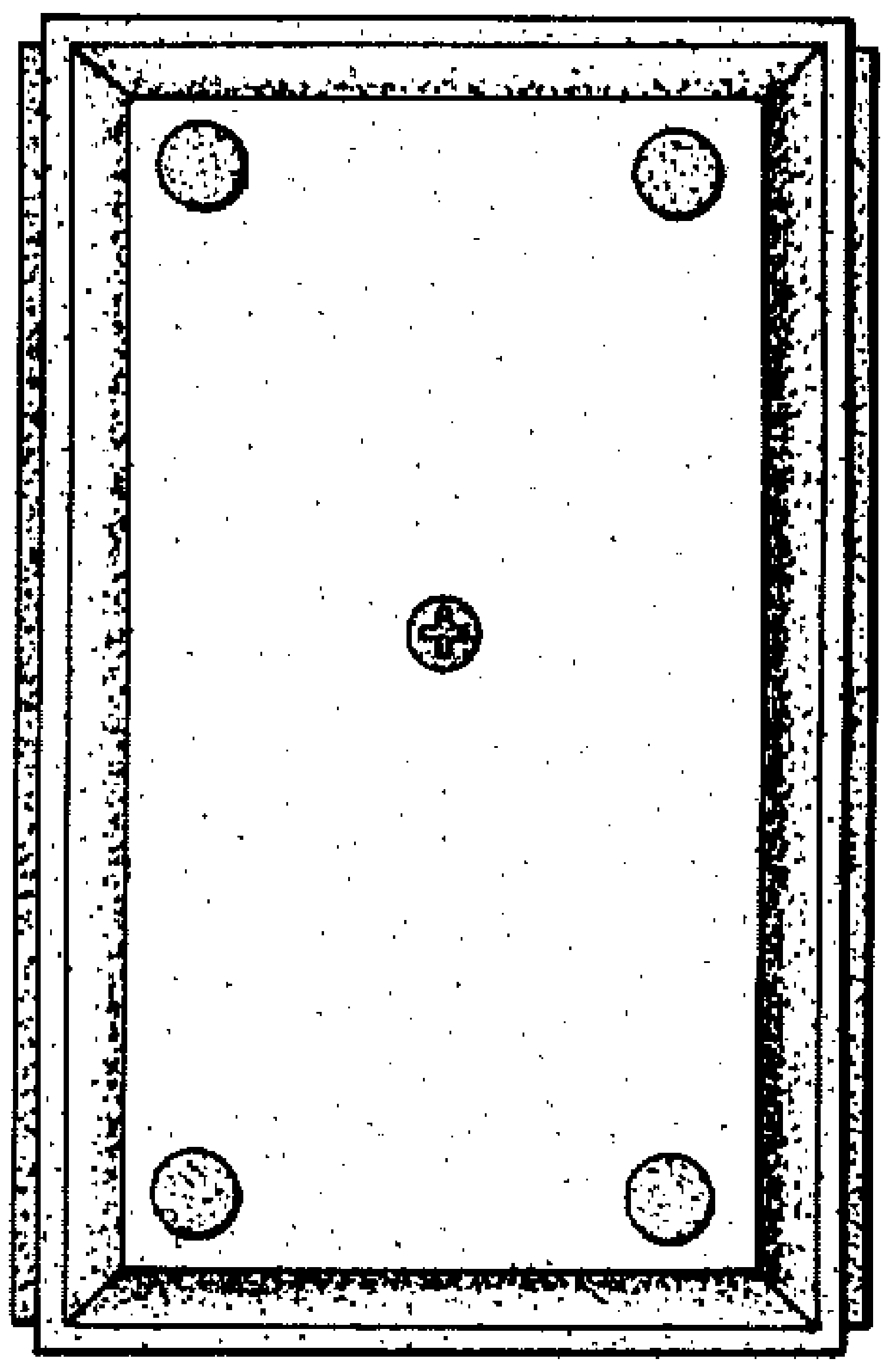

FIG. 7

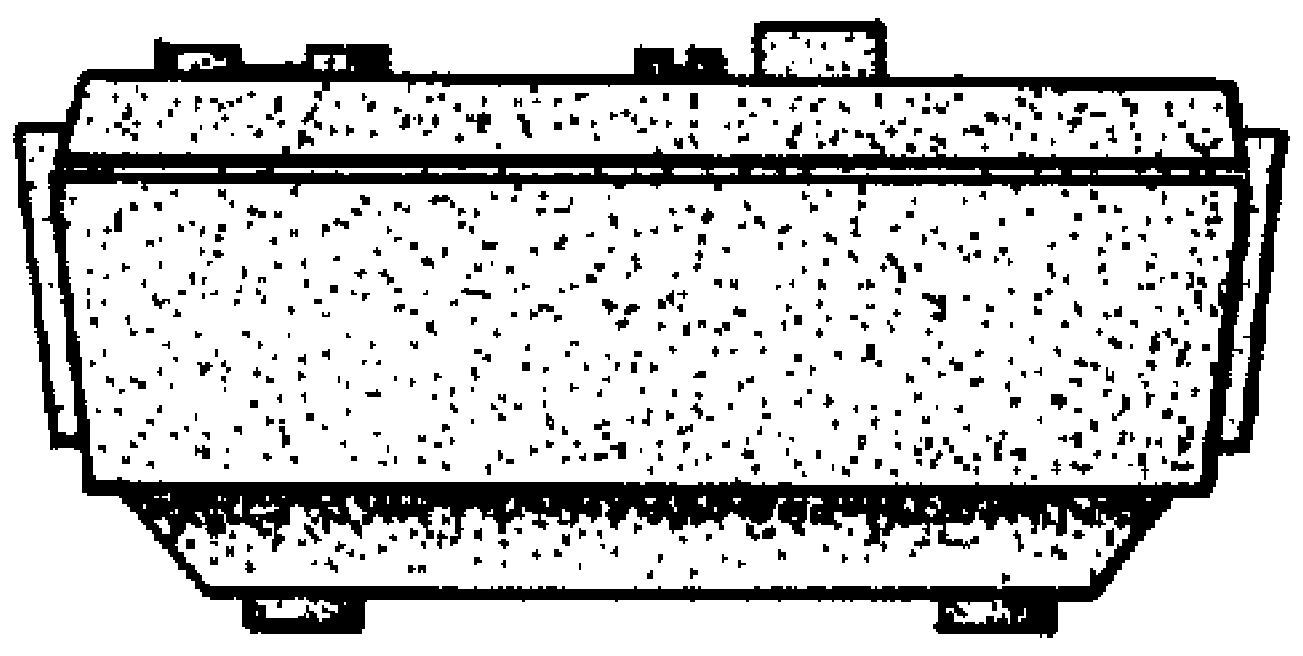

FIG. 6